

US-PAT-NO: 6275051
 DOCUMENT-IDENTIFIER: US 6275051 B1
 TITLE: Segmented architecture for wafer test and burn-in

----- KWIC -----

US Reference Patent Number - URPN (4):
 5945834

Details Text Image HTML KWIC

	Document ID	Kind Codes	Source	Issue Date	Pages	
6	US 6357025 B1		USPAT	20020312	11	Tes
7	US 6349396 B1		USPAT	20020219	18	Tes
8	US 6340895 B1		USPAT	20020122	34	Waf
9	US 6340838 B1		USPAT	20020122	11	App
10	US 6320397 B1		USPAT	20011120	13	Mol
11	US 6297658 B1		USPAT	20011002	19	Waf
12	US 6275051 B1		USPAT	20010814	35	Seg

Details Text Image HTML

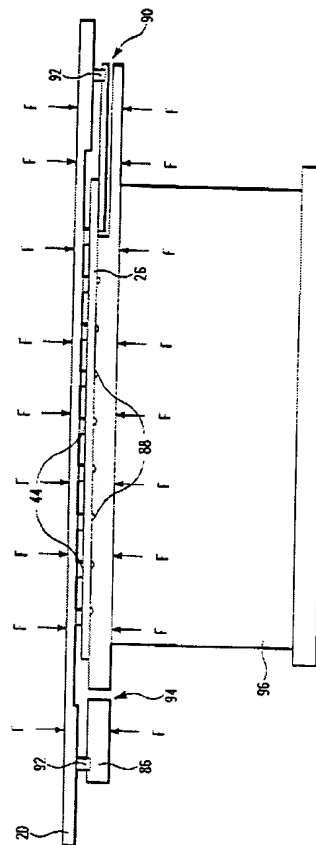


FIG. 7b

Details Text Image HTML Full